


<b>Search Notes</b>  	<b>Application/Control No.</b>  10572798	<b>Applicant(s)/Patent Under Reexamination</b>  ADACHI ET AL.
	<b>Examiner</b>  Chau N Nguyen	<b>Art Unit</b>  2831

SEARCHED			
Class	Subclass	Date	Examiner
174	73.1	1/31/08	CN

SEARCH NOTES		
Search Notes	Date	Examiner
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INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner